Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination		
10/522,698	KURIMURA ET AL.		
Examiner	Art Unit		
John D. Lee	2874		

SEARCHED						
Class	Subclass	Date	Examiner			
359	326-332	7/6/2006	JDL			
385	122	7/6/2006	JDL			

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		

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DATE	EXMR
7/6/2006	JDL.
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